

---

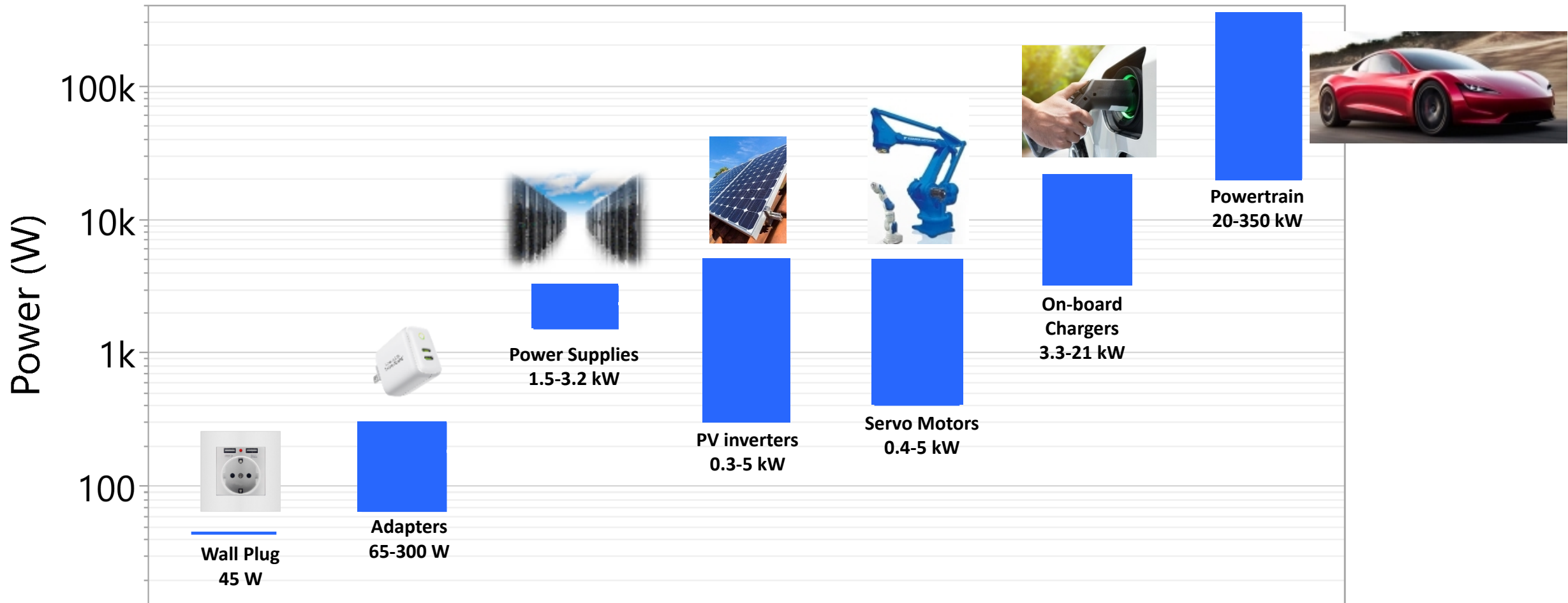
# High-Power 650-V and 1200-V GaN Devices for EVs Applications

D. Bisi, G. Gupta, C. J. Neufeld, Y. Huang, T. Hosoda, M. Kanamura, R. Lal.,  
L. Shen, T. Dhayagude, P. Zuk, P. Parikh, U. K. Mishra



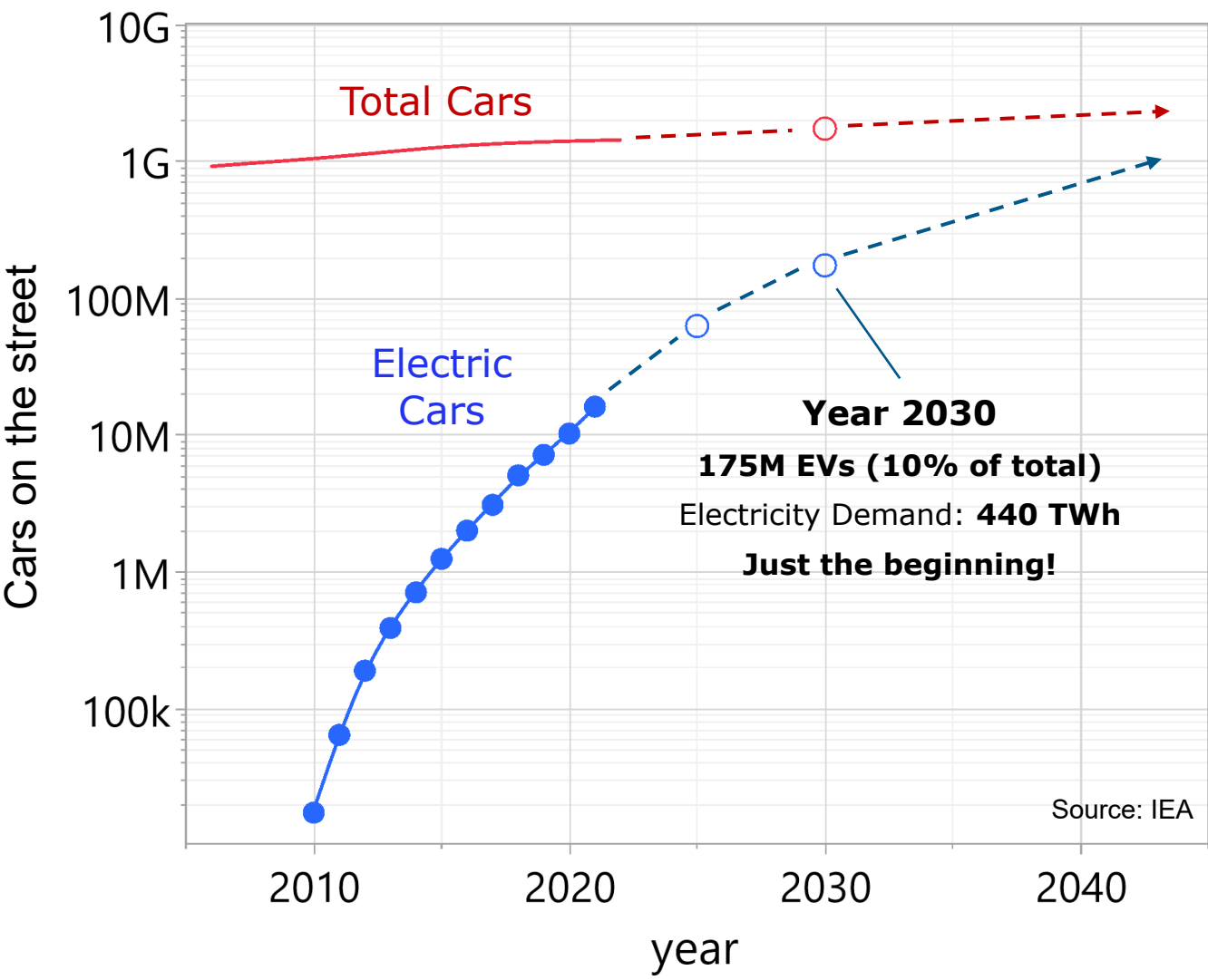
Presented at APEC, March 21<sup>st</sup> 2023

# Broad power spectrum, one common challenge: Volume constraint



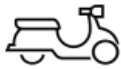
GaN can serve them all, efficiently.

# Zero Emission Vehicles: Worldwide Policies & Manufacturers Pledges



|            | EV Target Sales     | Target Date |
|------------|---------------------|-------------|
| Volvo      | 100%                | 2030        |
| Ford       | 100% in Europe      | 2030        |
| GM         | 100% (LDVs)         | 2035        |
| Volkswagen | 70% Europe; 50% USA | 2030        |
| Stellantis | 70% Europe; 35% USA | 2030        |

and many more.

  
**2W**

  
**3W**

  
**4W**

  
**Bus**

# The Electric Vehicle

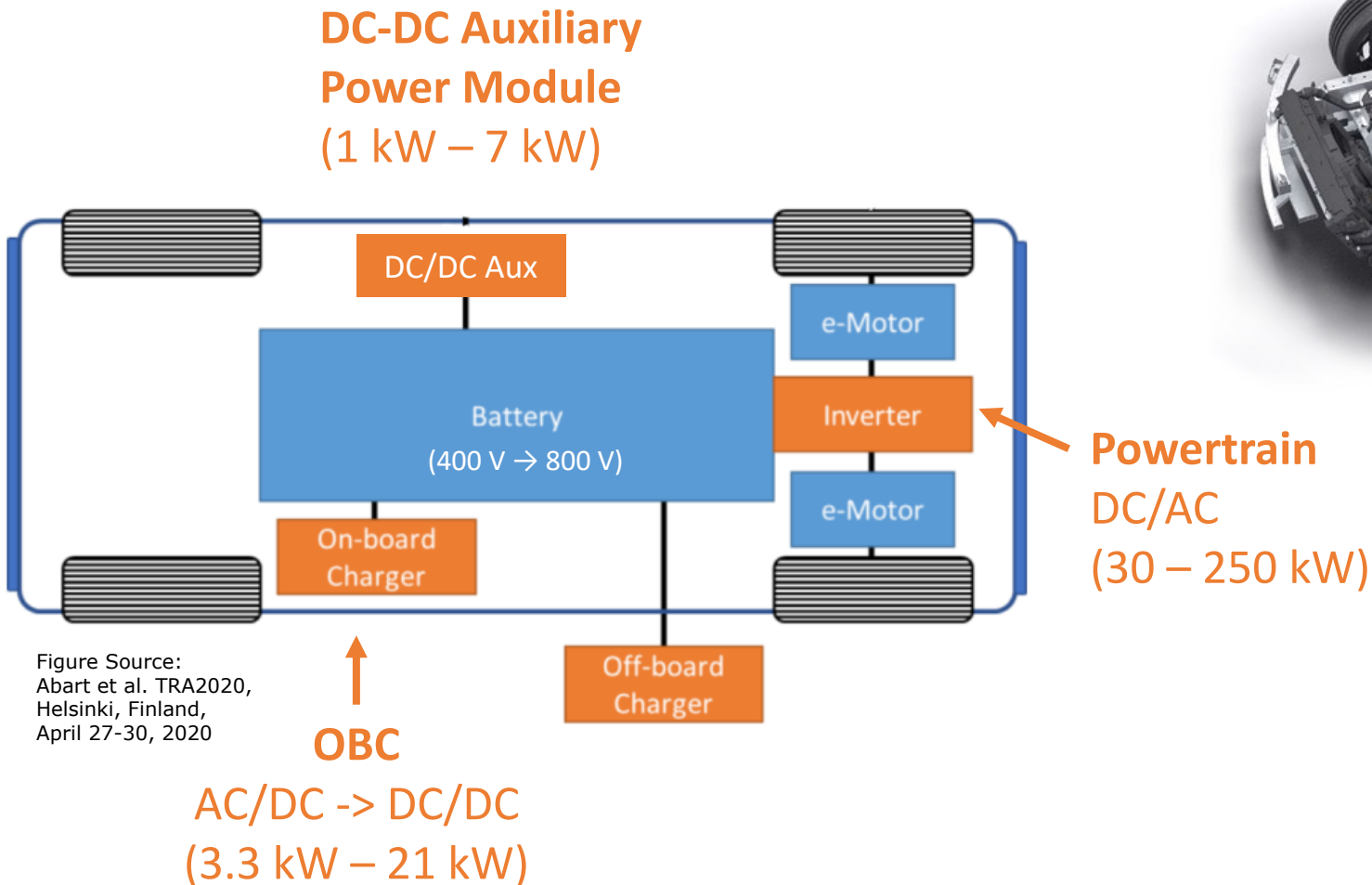


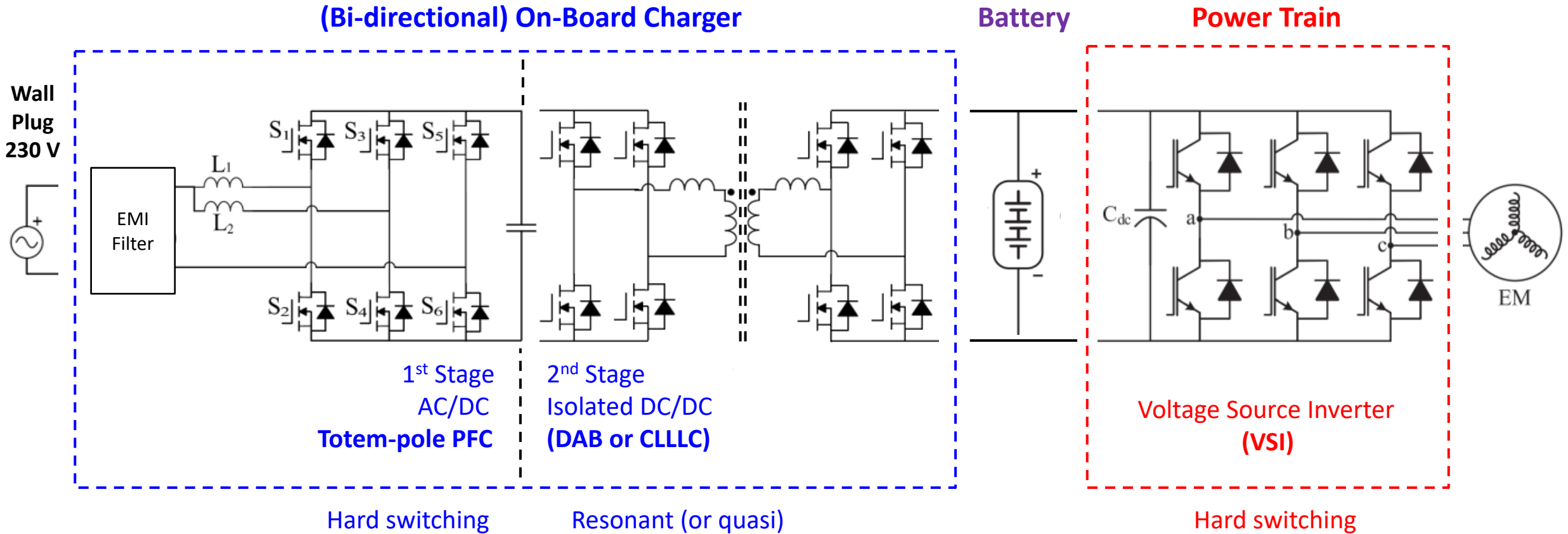
Figure Source:  
Abart et al. TRA2020,  
Helsinki, Finland,  
April 27-30, 2020



## Requirements:

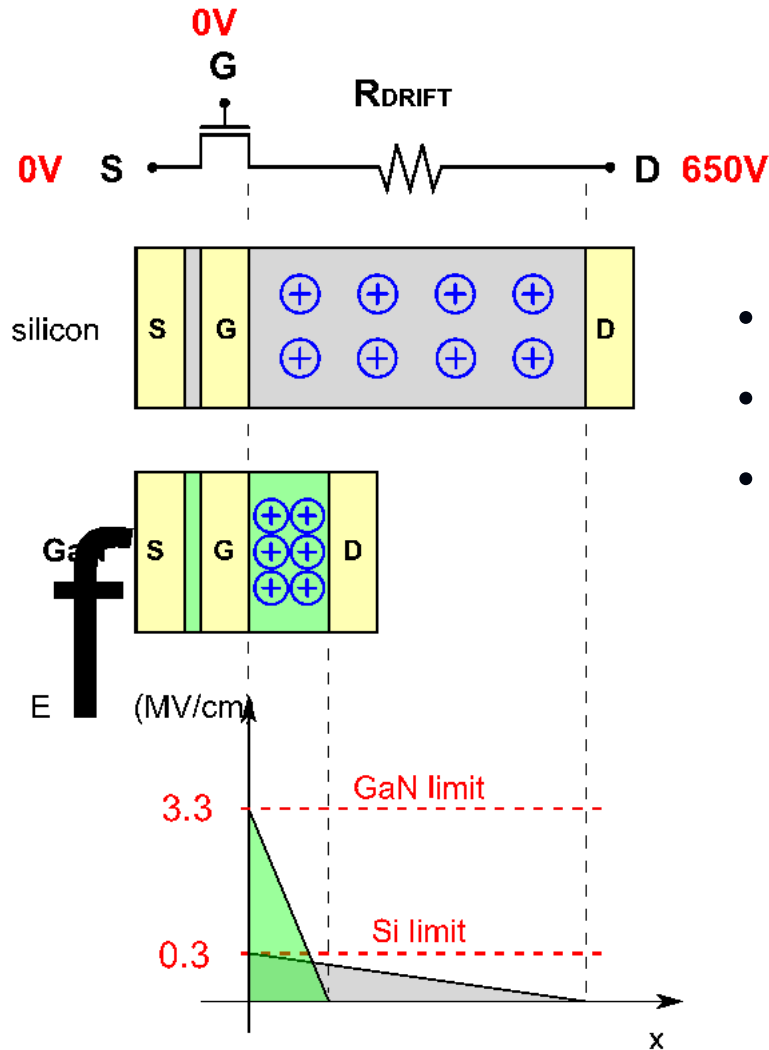
Efficiency  
Power  
Reliability

# From Wall to Wheel



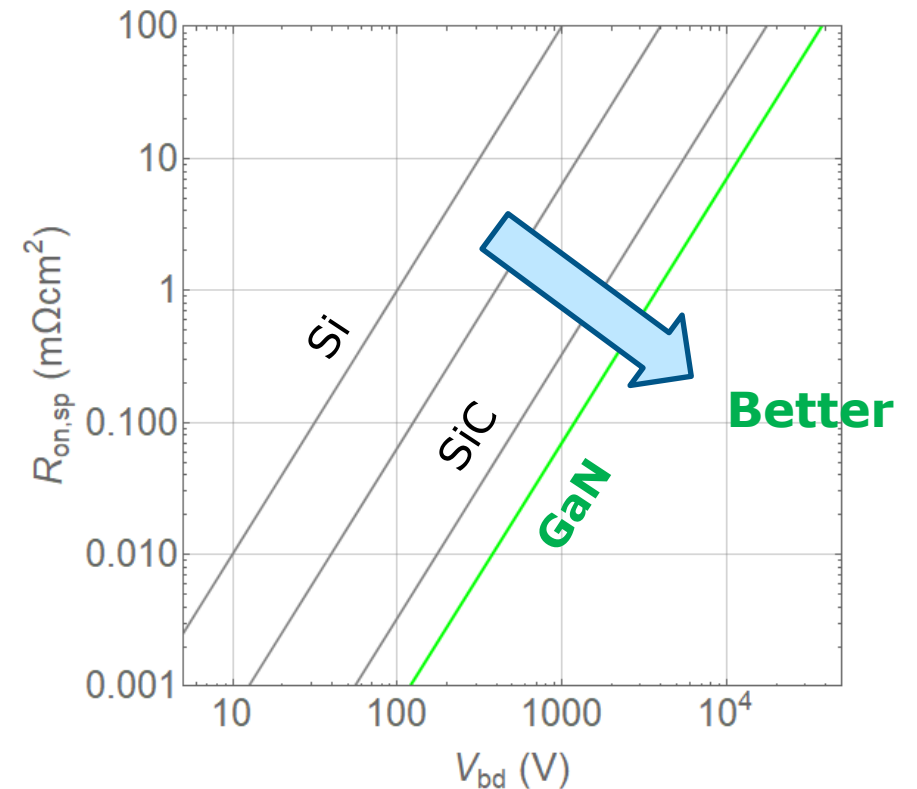
Volume constraint: High frequency & high efficiency are a must

# GaN: same Voltage Rating, superior Switching Performance than Silicon

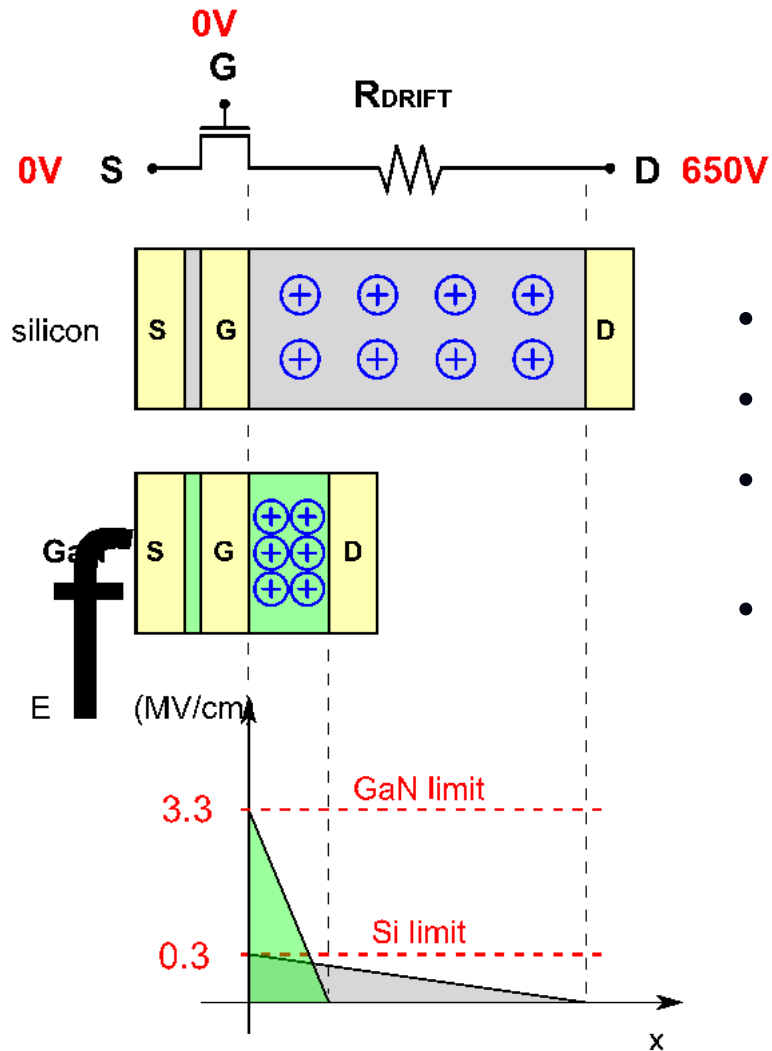


- Higher Critical field
- Higher Mobility
- Lower Specific Ron

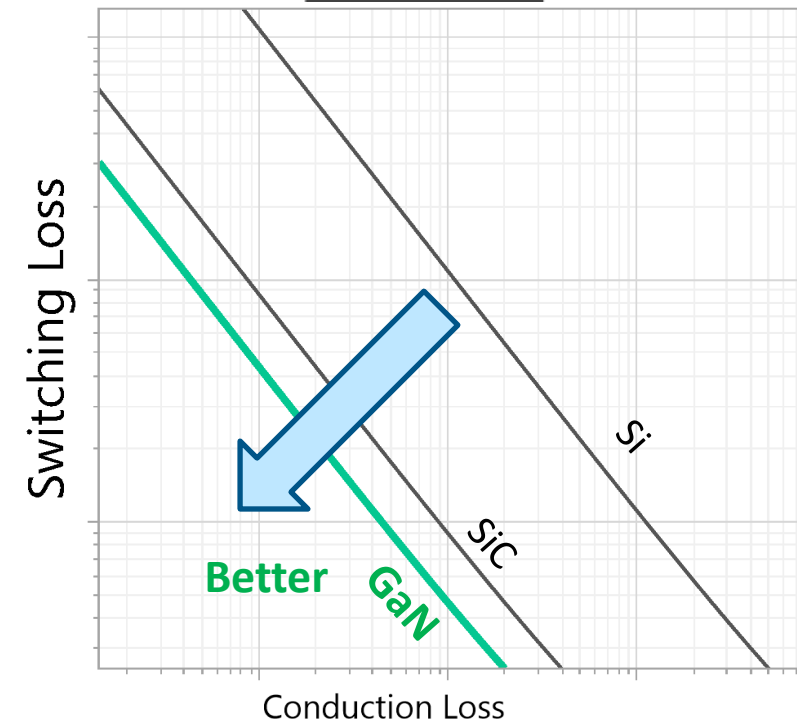
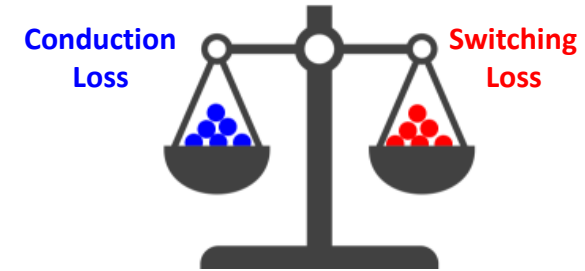
$$R_{on,sp} = \frac{4V_{bd}^2}{\epsilon \cdot \mu \cdot E_c^3}$$



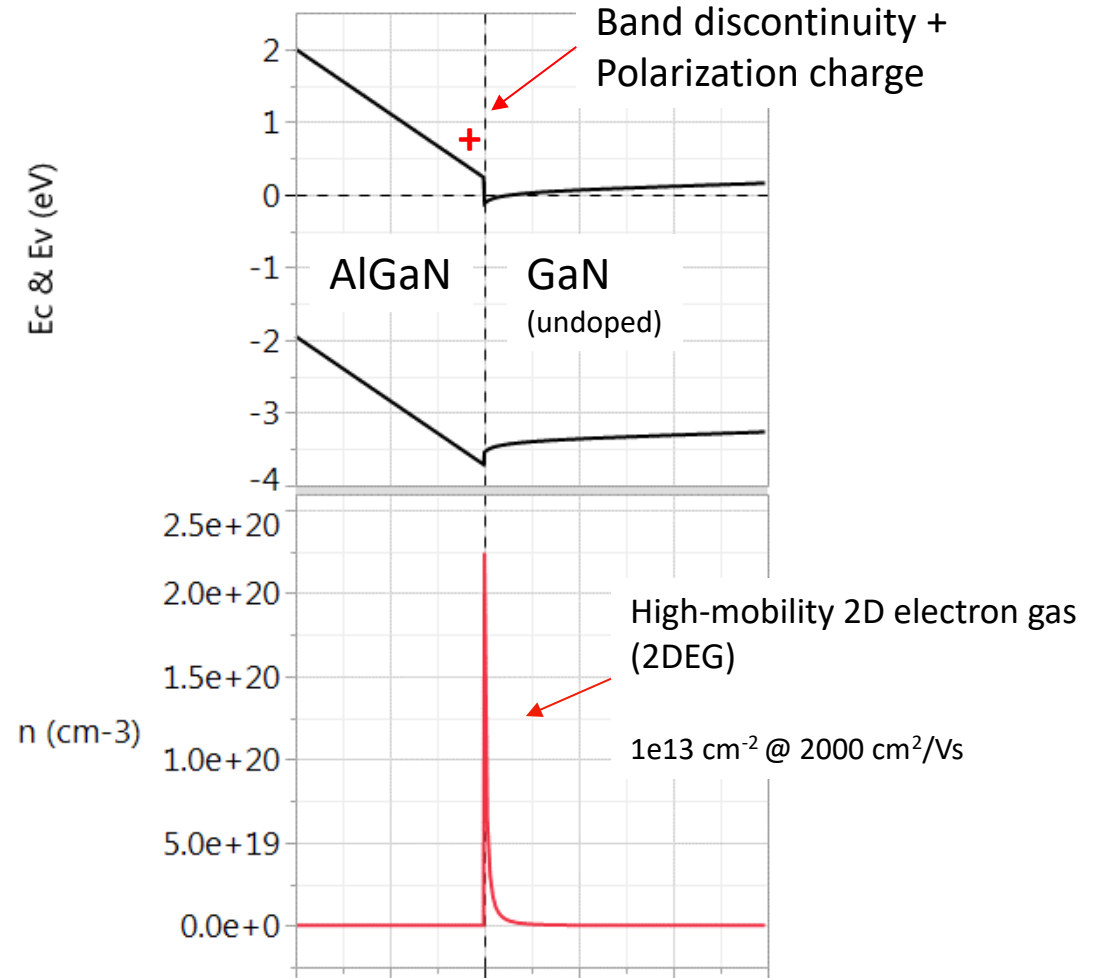
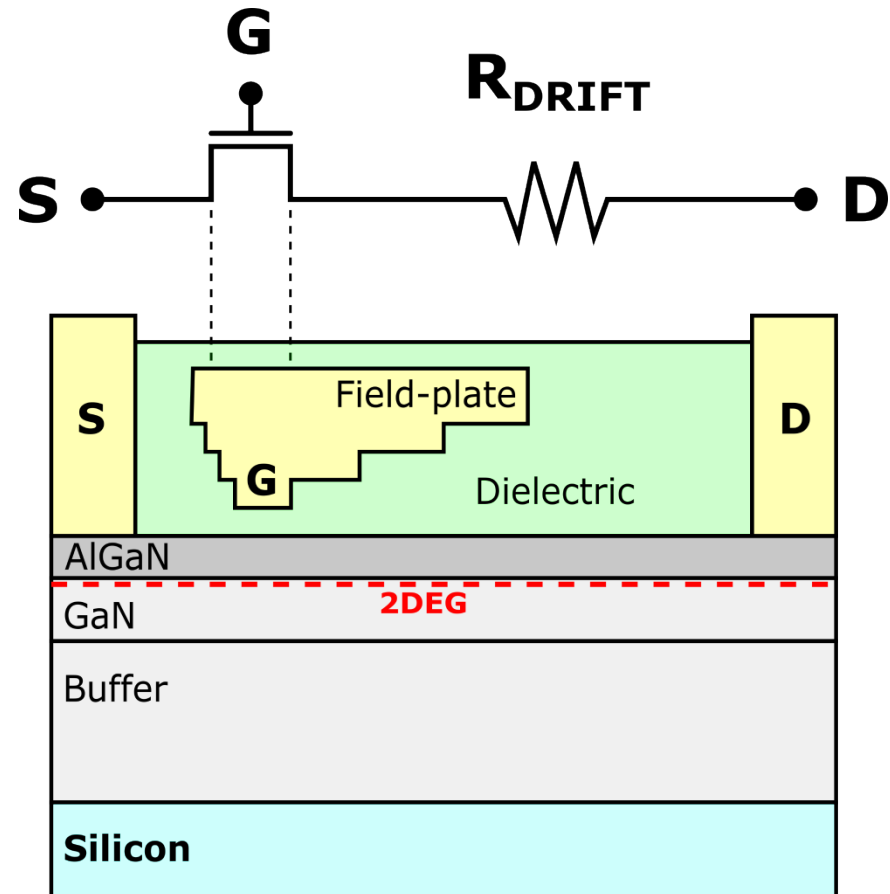
# GaN: same Voltage Rating, superior Switching Performance than Silicon



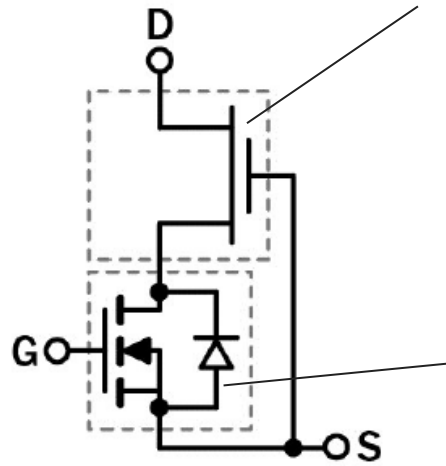
- Higher Critical field
- Higher Mobility
- Smaller stored charge
- Higher FOMs
  - $R_{on} \cdot Q_G$
  - $R_{on} \cdot Q_{OSS}$
  - $R_{on} \cdot Q_{RR}$



# Transphorm GaN HEMTs



# Transphorm normally-off GaN: Two-chip Cascode



## GaN HEMT:

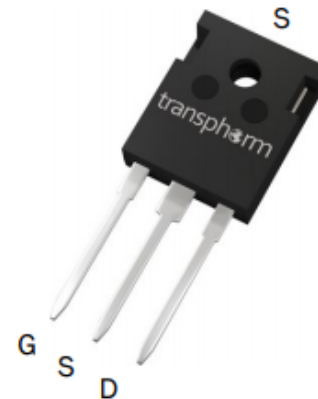
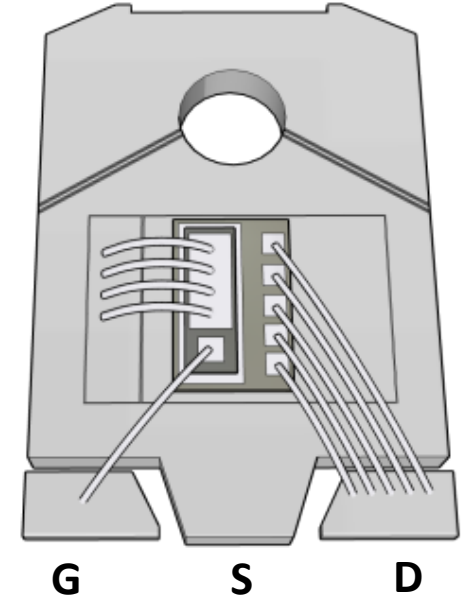
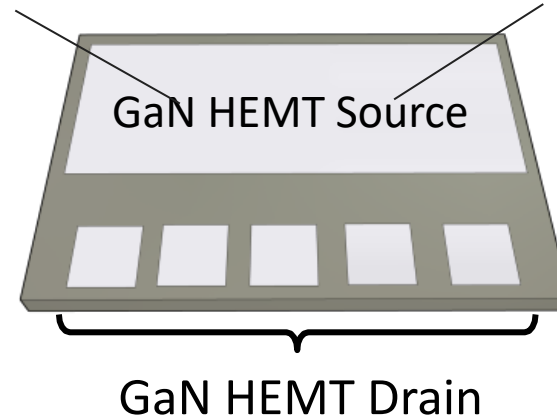
- High voltage ( $\geq 650\text{V}$ )
- High speed

## Silicon MOSFET ( $\leq 30\text{V}$ ):

- Insulated & Normally-off
- High speed
- High Threshold (4 V)
- High  $V_g$  Rating ( $\pm 20\text{V}$ )

Si-FET gate

Si-FET source

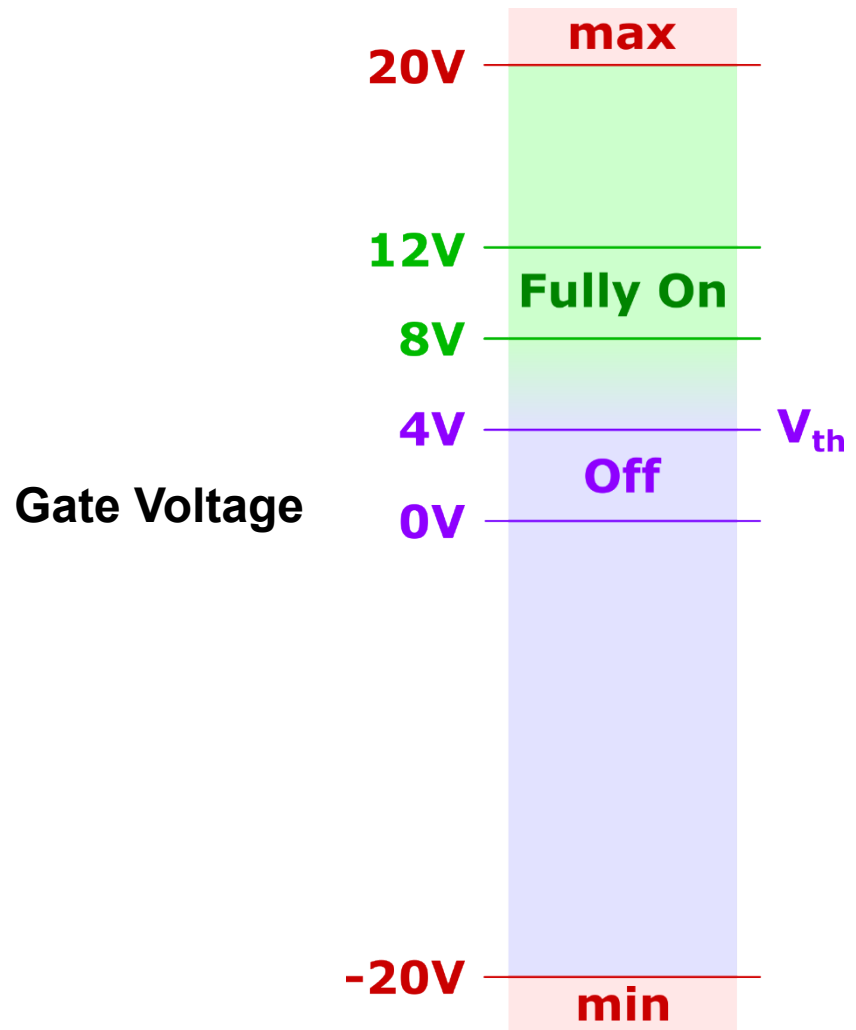


JEDEC  
qualified

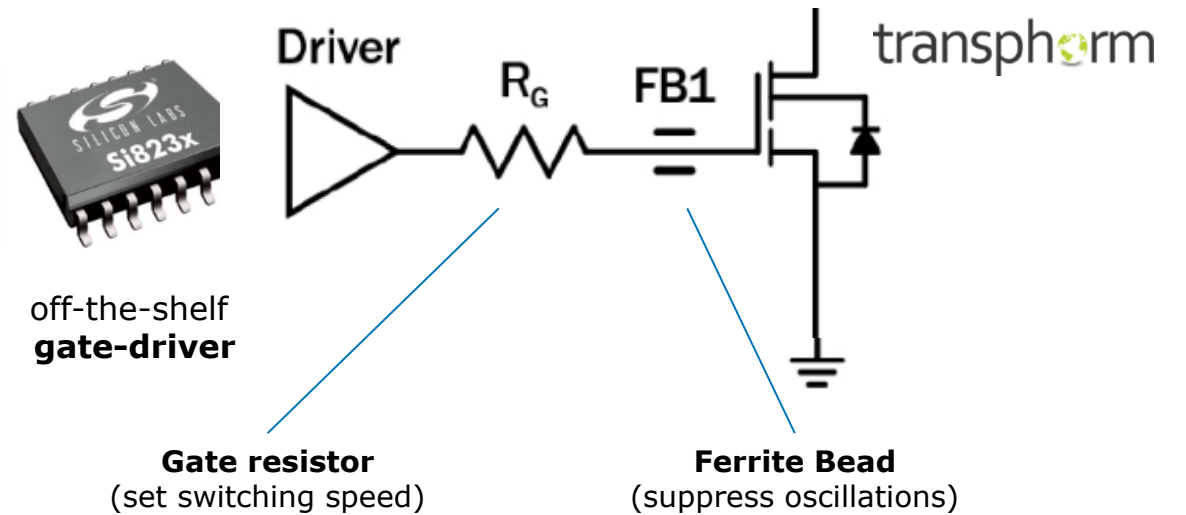


AEC-Q101  
qualified  
(150°C & 175°C)

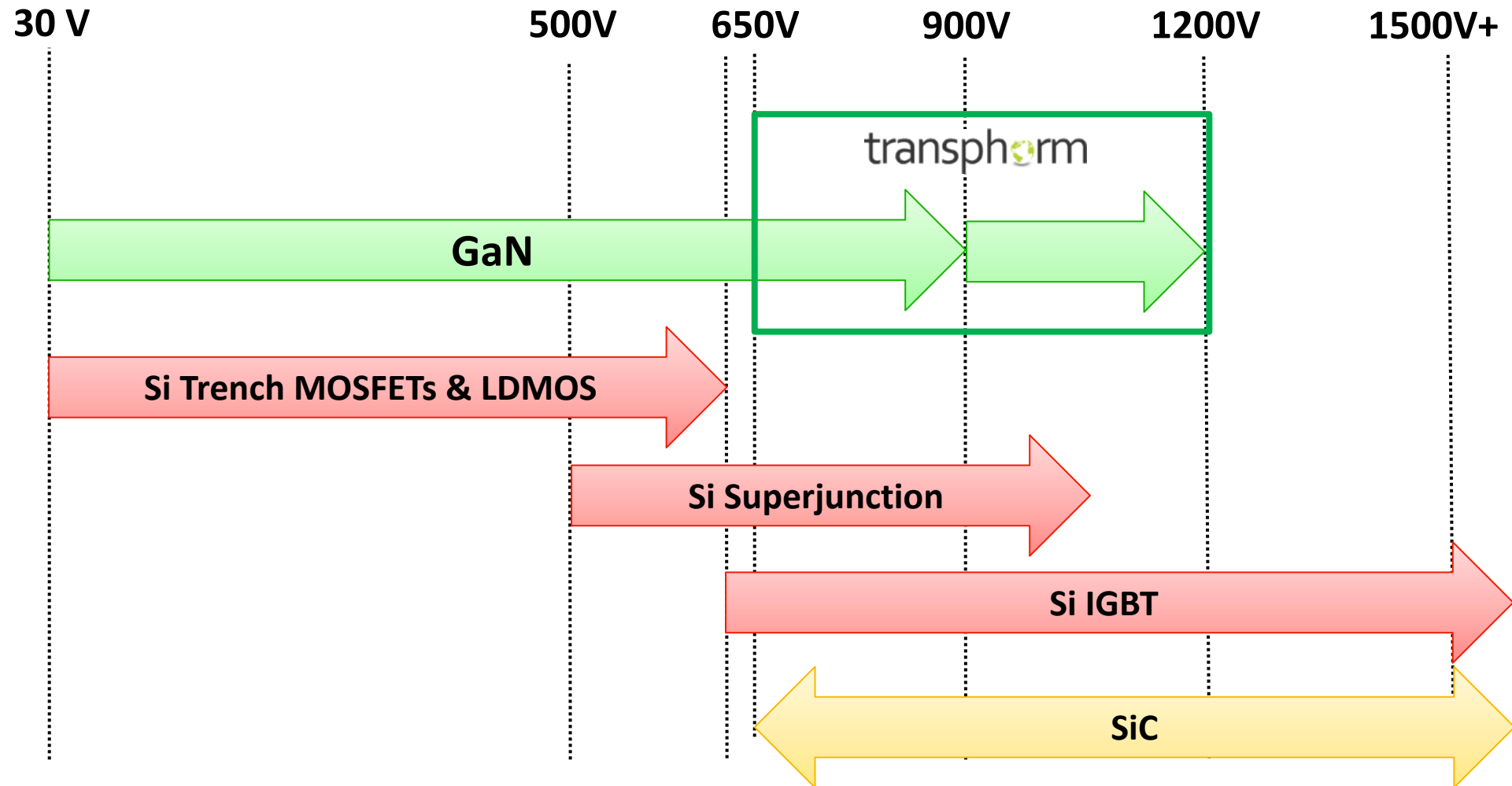
# Driving Transphorm GaN



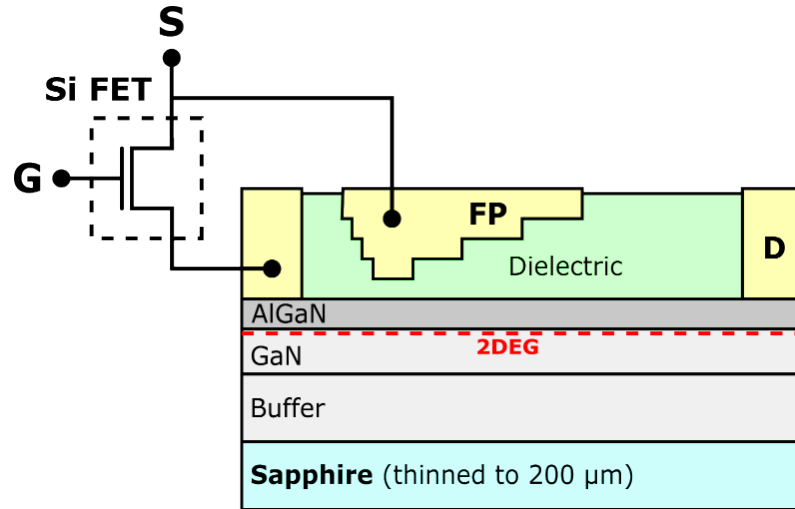
- High Threshold (+4 V)
- Fully-on at +12 V
- High Gate Rating ( $\pm 20$  V)
- Compatible with standard gate drivers



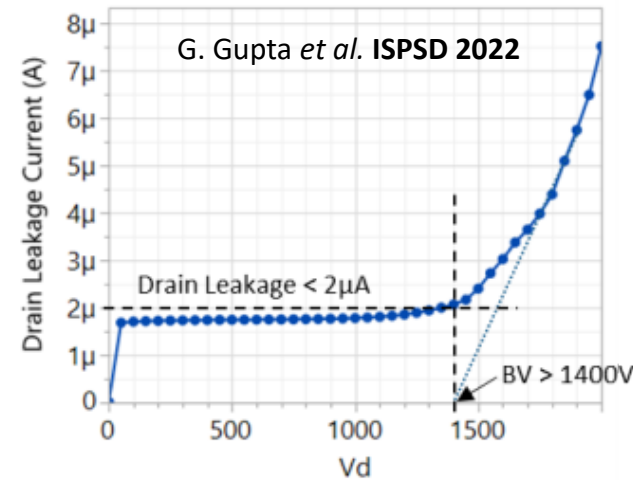
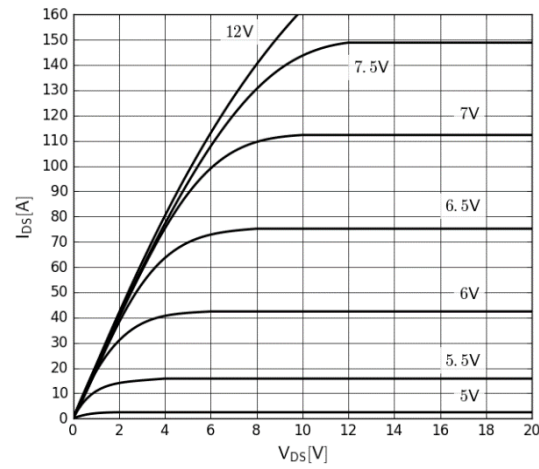
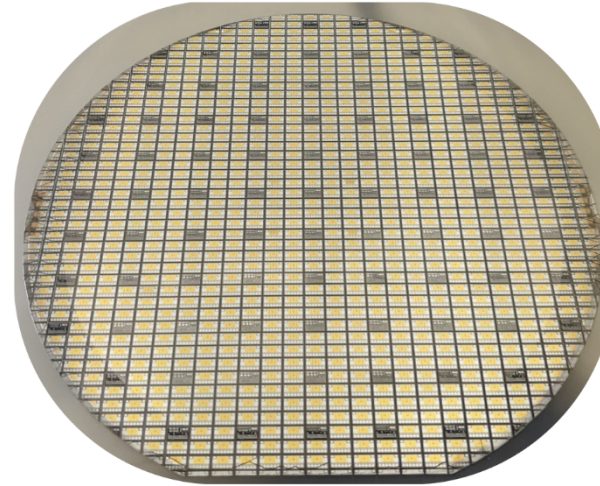
# Voltage Rating



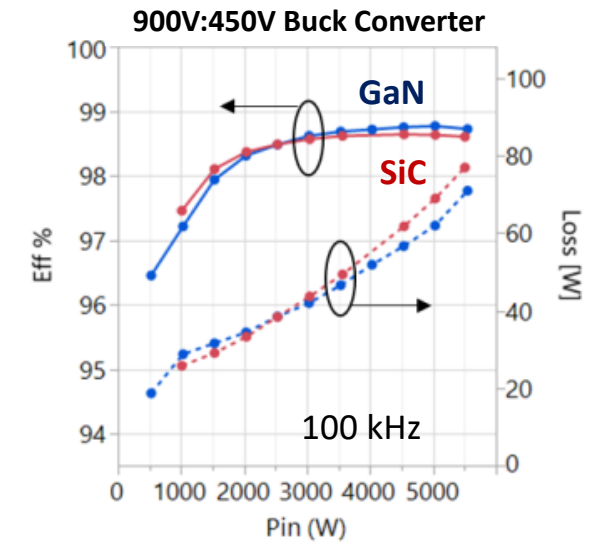
# Low-Cost, High-performance 1200-V GaN



1200-V GaN HEMTs on 6" sapphire



G. Gupta *et al.* ISPSD 2022

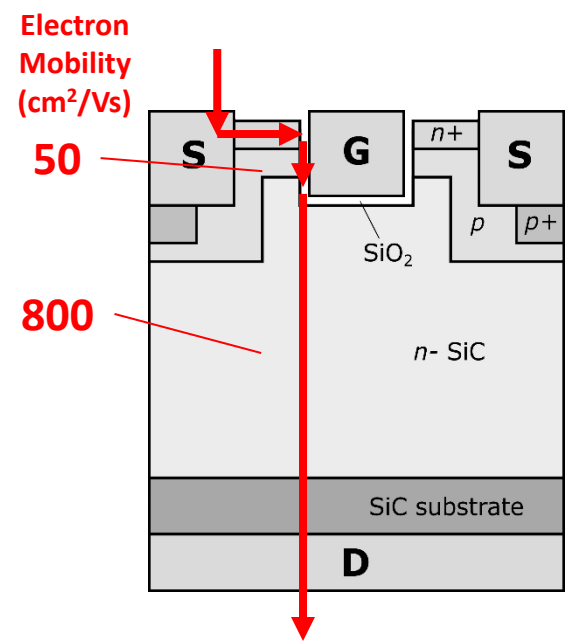


IS03.1

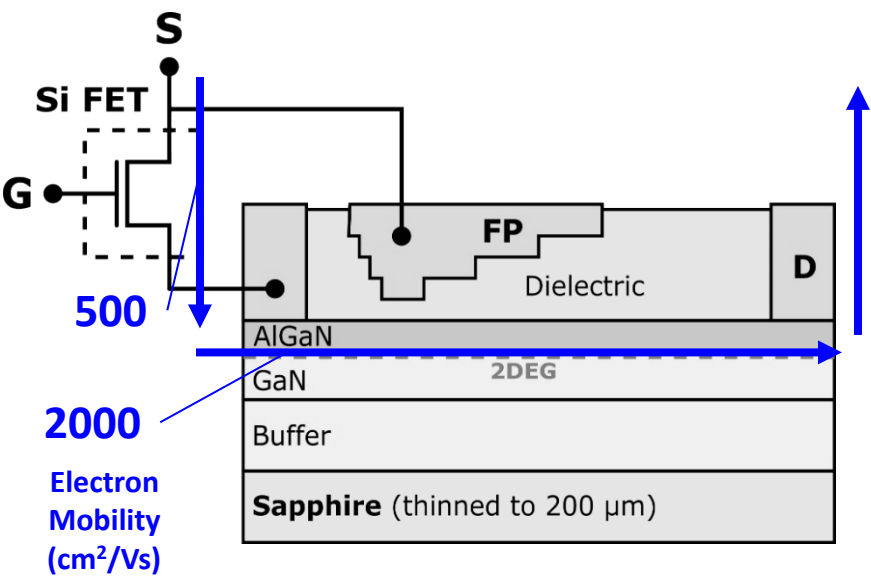


# GaN vs. SiC: Higher Mobility, Less Charge

SiC MOSFET



GaN HEMT

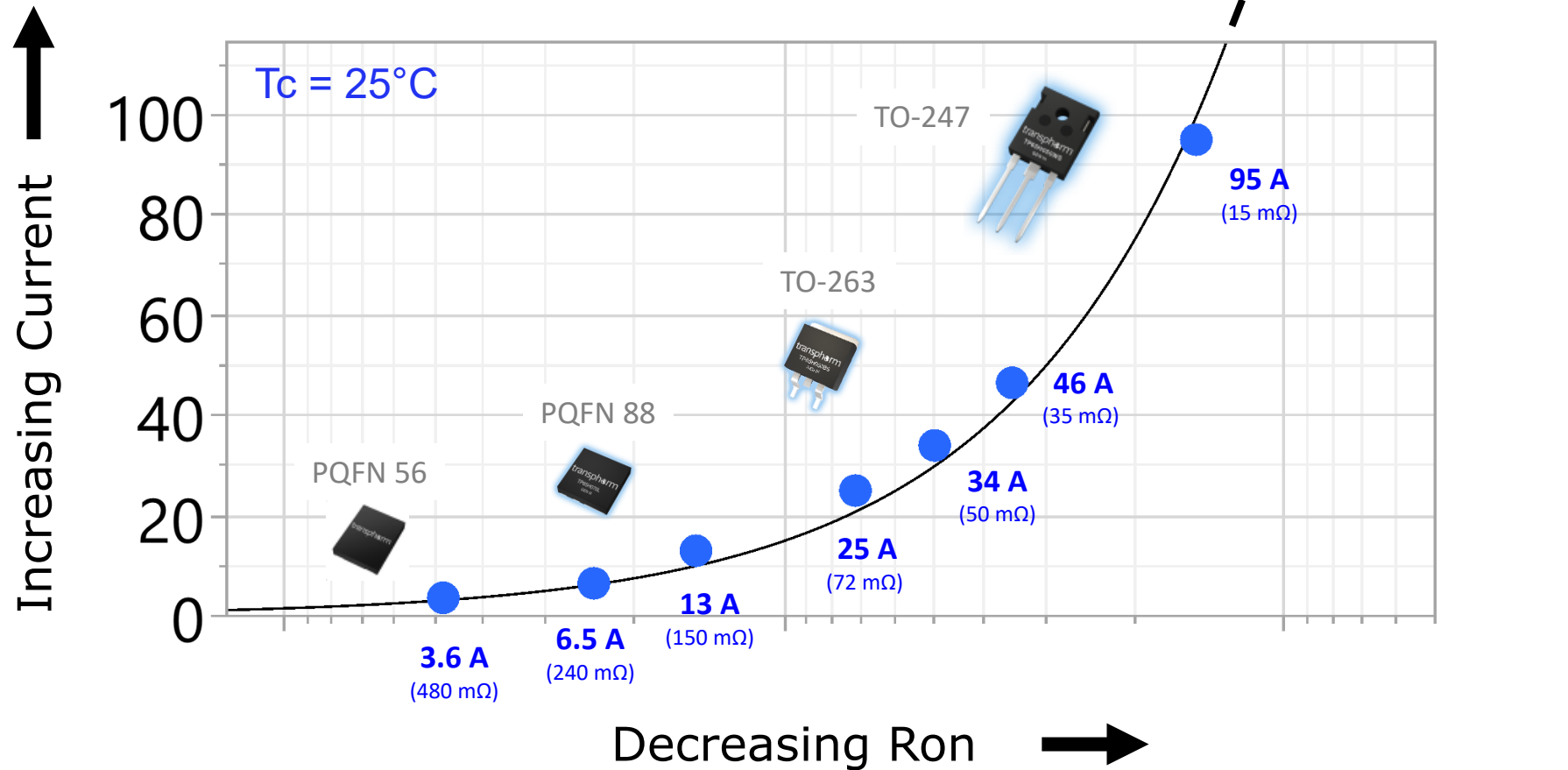


|                                | SiC    | GaN  |
|--------------------------------|--------|------|
| Voltage Rating (V)             | 1200   | 1200 |
| R <sub>on</sub> (mΩ)           | 75     | 70   |
| Q <sub>G</sub> (nC)            | 54     | 15   |
| Q <sub>GD</sub> (nC)           | 20     | 5    |
| Q <sub>RR</sub> (nC)           | 279    | 185  |
| R <sub>th,j-c</sub> (°C/W)     | 0.97   | 0.93 |
| I <sub>d,max</sub> (A @ 100°C) | 23     | 20   |
| Material Cost                  | \$\$\$ | \$\$ |

- Higher electron mobility, less gate charge, higher frequency performance.
- Projected lower material cost structure.

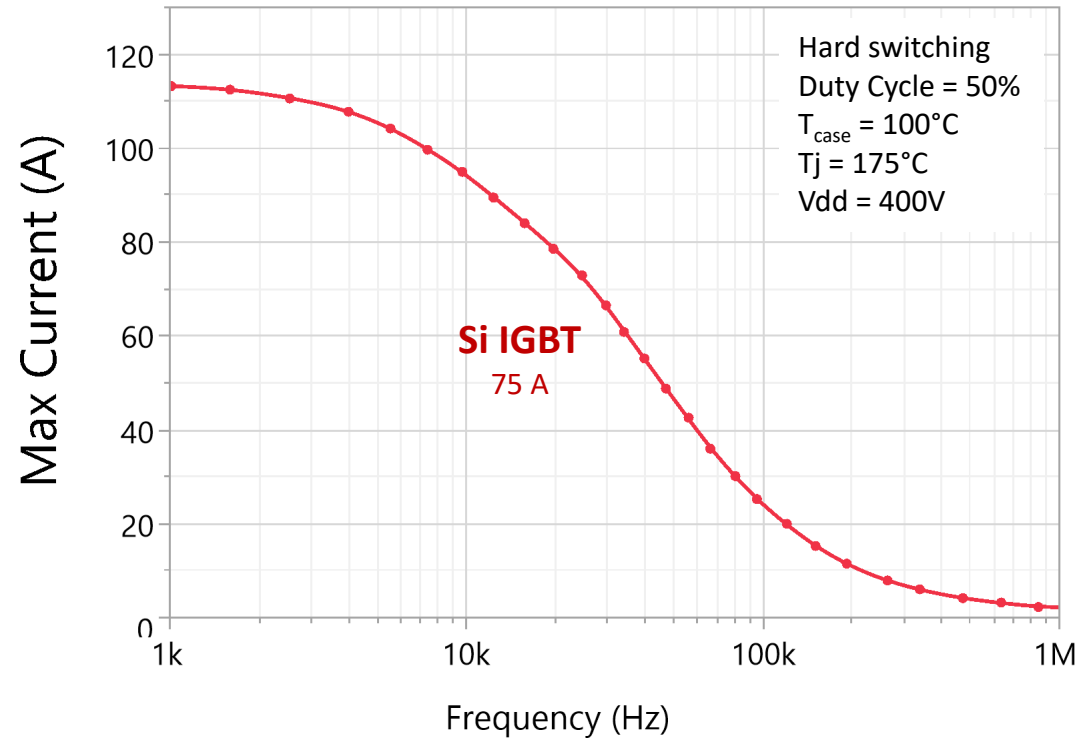


# DC Current Rating



Comprehensive portfolio, to cover wide range of power applications.

# Switching Current Rating



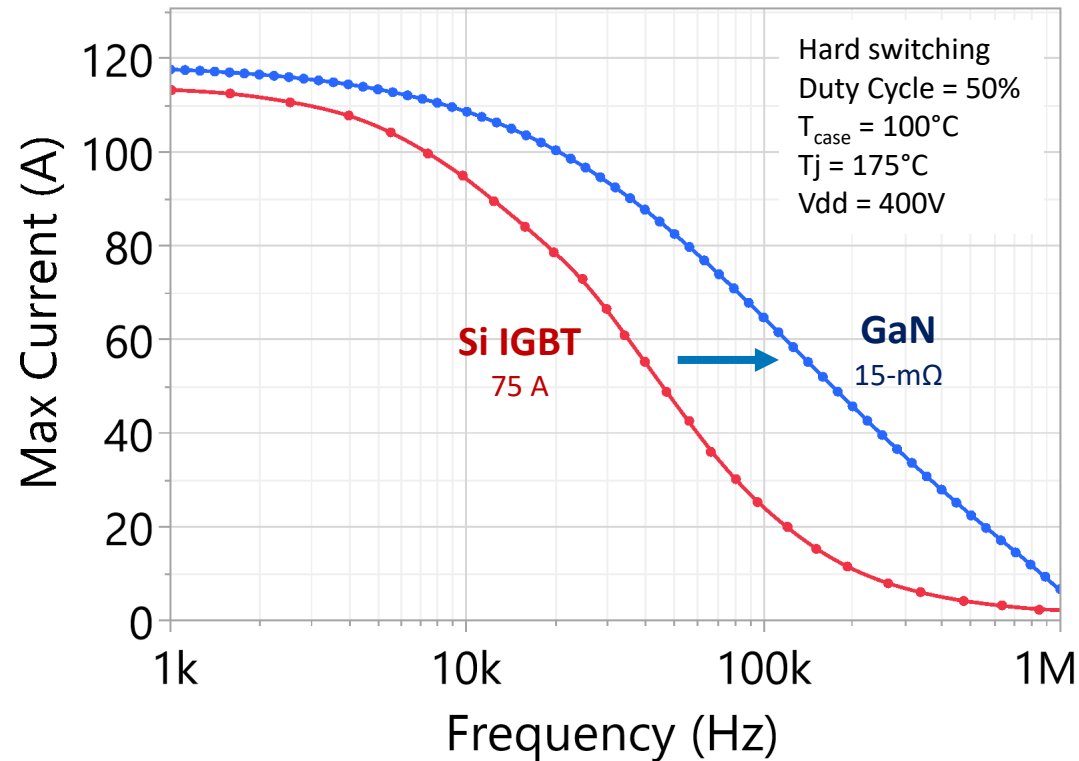
Rated current decreases with frequency due to switching losses

|               | Si IGBT     |
|---------------|-------------|
| Device Rating | 75 A        |
| Qg (nC)       | <b>225</b>  |
| Qgd (nC)      | <b>87</b>   |
| Qrr (nC)      | <b>high</b> |

$$\Delta T = R_{th} \cdot \left[ \underbrace{R_{on,dy} \cdot I_d^2 \cdot D}_{\text{Conduction Loss}} + \underbrace{f \cdot (E_{on} + E_{off})}_{\text{Switching Loss}} \right]$$



# Switching Current Rating



## GaN HEMT cascode:

- Smaller stored charge
- Smaller switching losses
- Superior current rating at high frequency, where it matters.

|               | Si IGBT | SiC MOSFET | GaN HEMT (cascode) |
|---------------|---------|------------|--------------------|
| Device Rating | 75 A    | 15 mΩ      | 15 mΩ              |
| Qg (nC)       | 225     | 188        | 74                 |
| Qgd (nC)      | 87      | 62         | 21                 |
| Qrr (nC)      | high    | 562        | 430                |

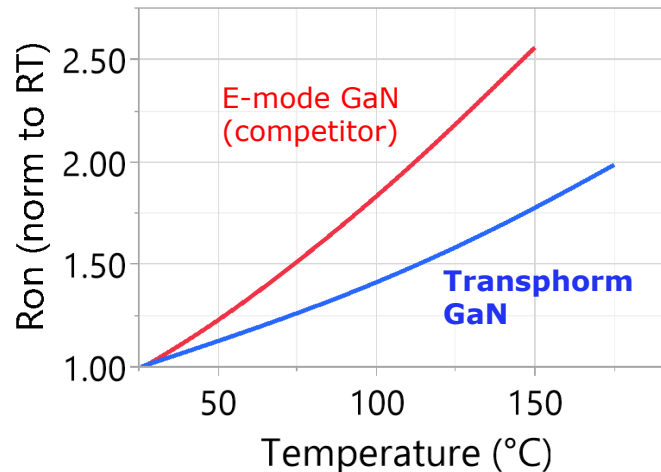
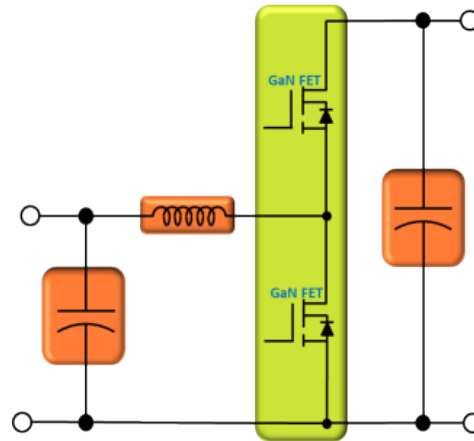
$$\Delta T = R_{th} \cdot \left[ \underbrace{R_{on,dy} \cdot I_d^2 \cdot D}_{\text{Conduction Loss}} + \underbrace{f \cdot (E_{on} + E_{off})}_{\text{Switching Loss}} \right]$$



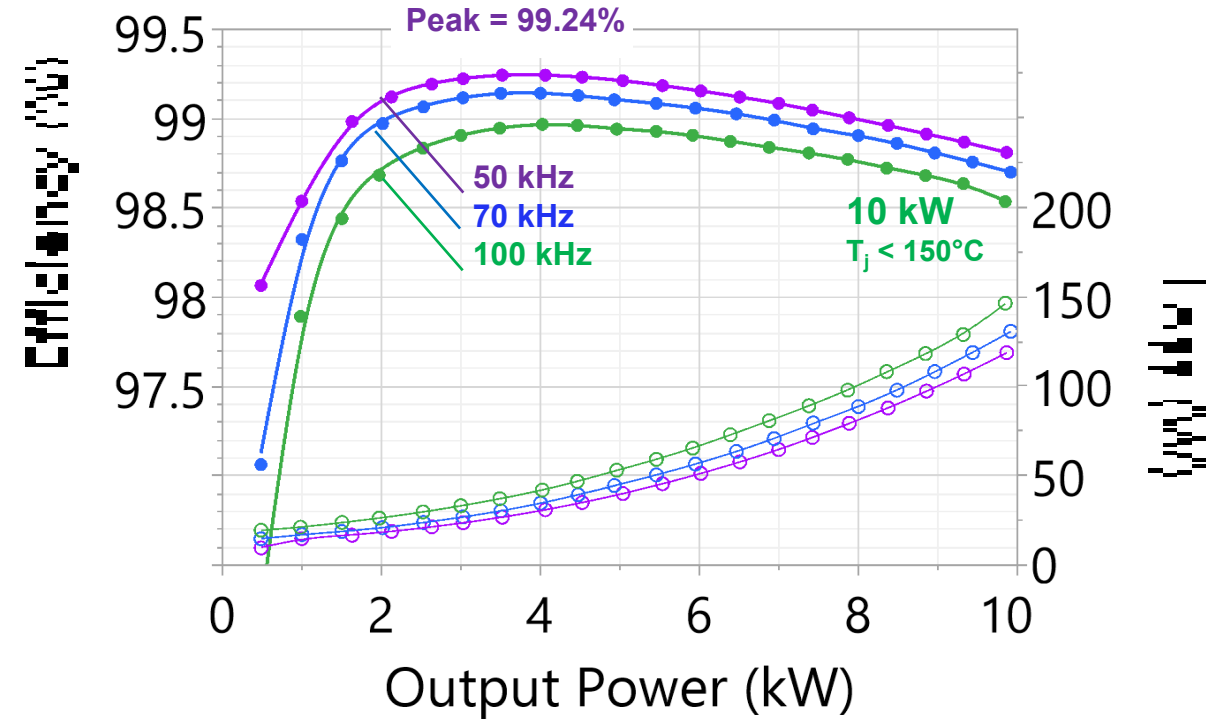
# Efficient Switching to 10 kW, 100 kHz

## 240V:400V DCDC CCM Boost

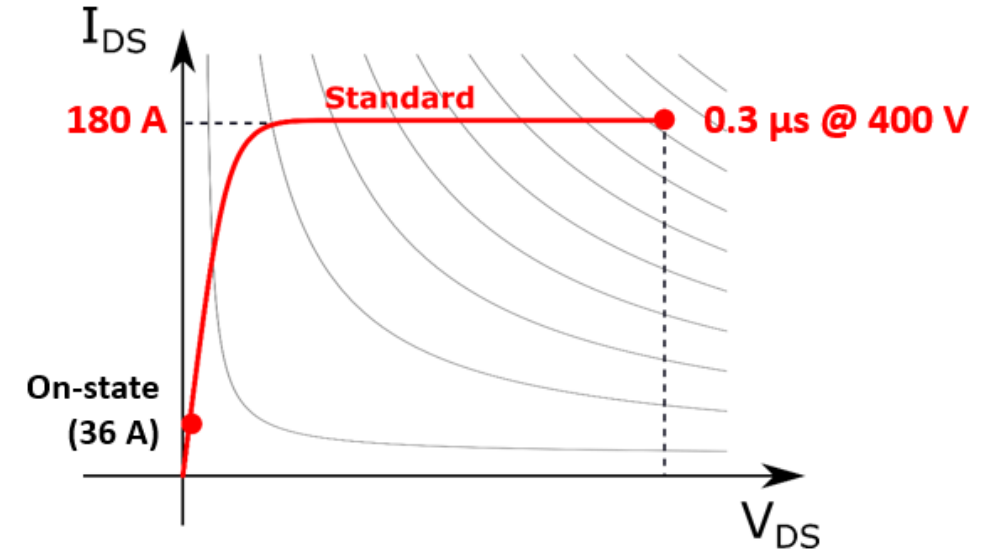
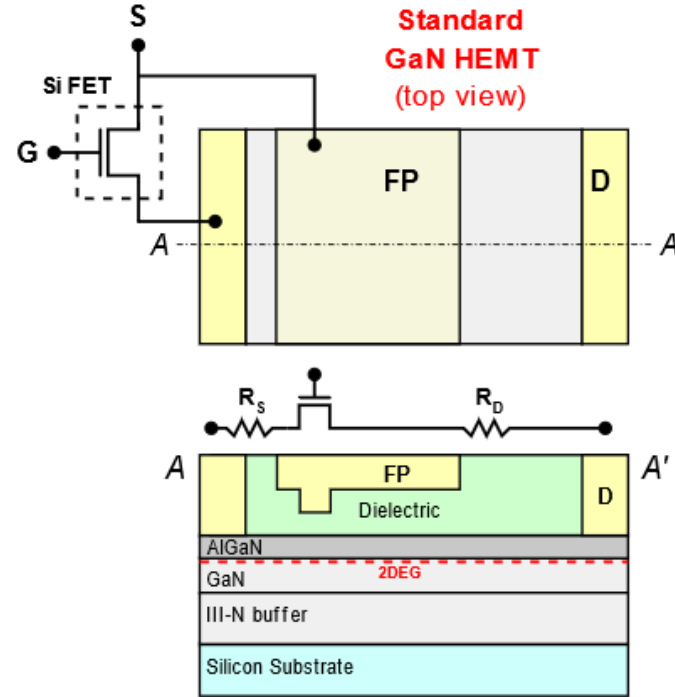
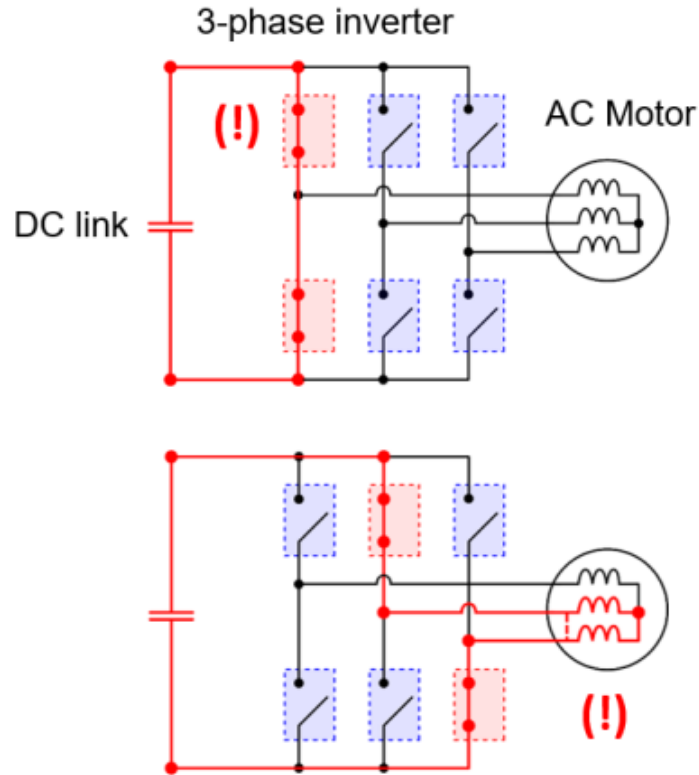
Gate Driver = **Si8285 (4 A)**  
Gate Voltage = **0-12 V**  
 $R_{g,on} = 5\ \Omega$   
 $R_{g,off} = 15\ \Omega$   
Deadtime = **300 ns**  
Ferrite Bead = **120  $\Omega$  at 100 MHz**  
DC Snubber = **10 nF + 2  $\Omega$**



Smaller  $R_{on}$   
temperature coefficient  
than E-mode competition

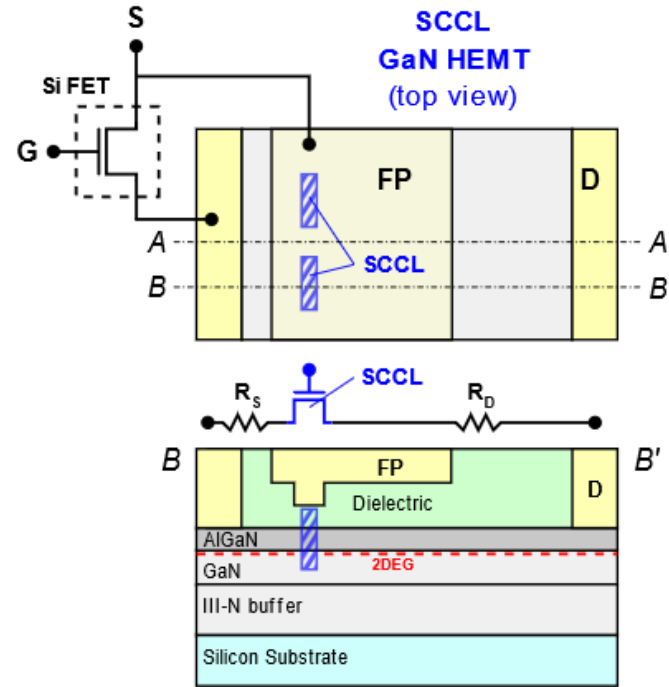
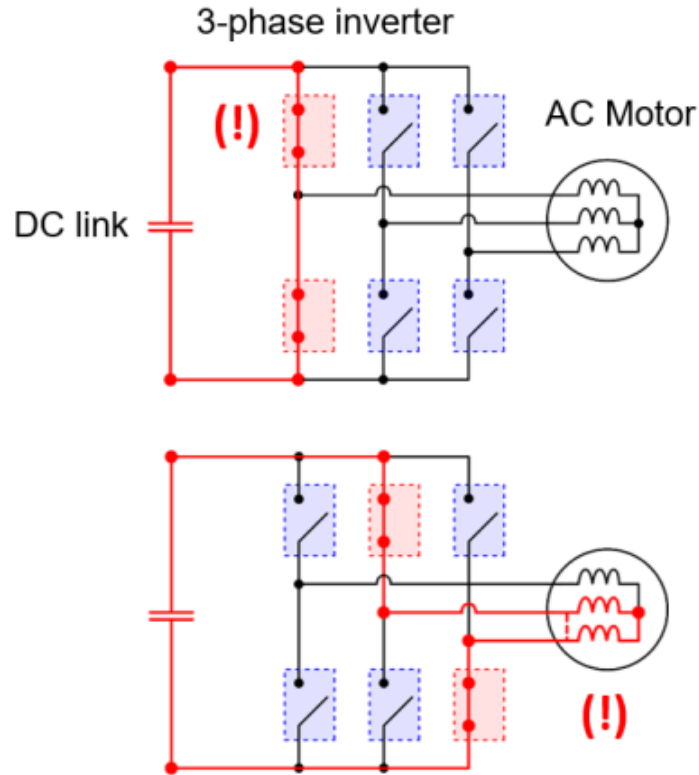


# Short-Circuit Capability

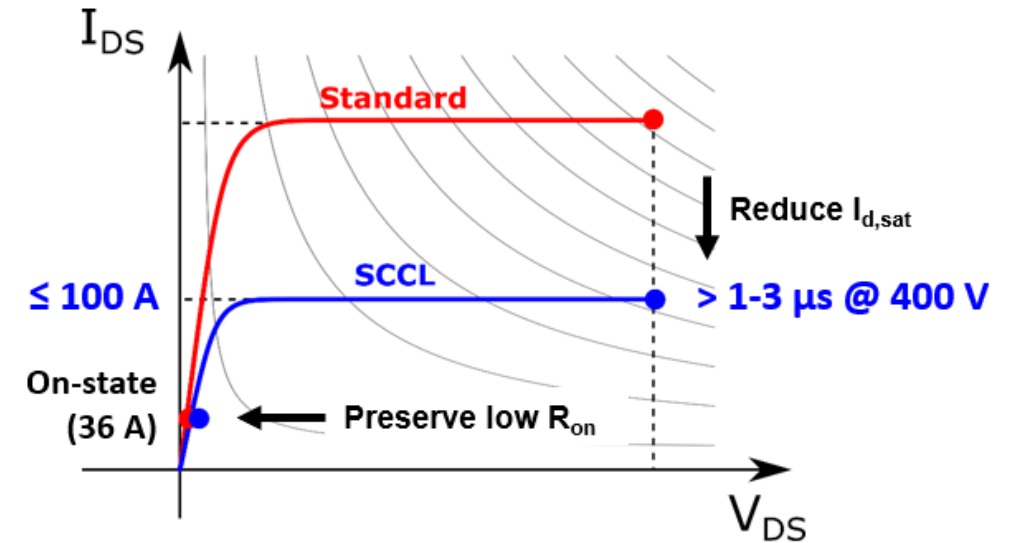


- Standard GaN HEMTs have high saturation current due to high performance 2DEG.
- Difficult to achieve short-circuit withstanding capability (!)

# Short-Circuit Capability

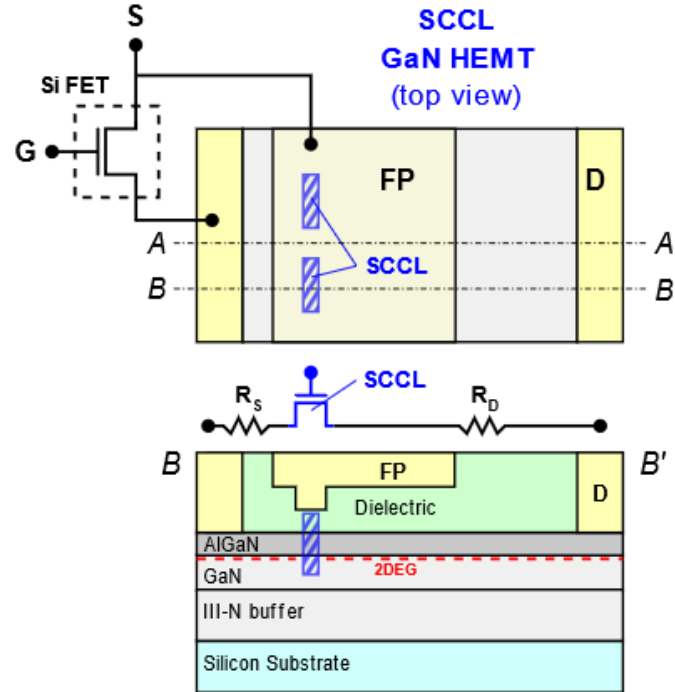
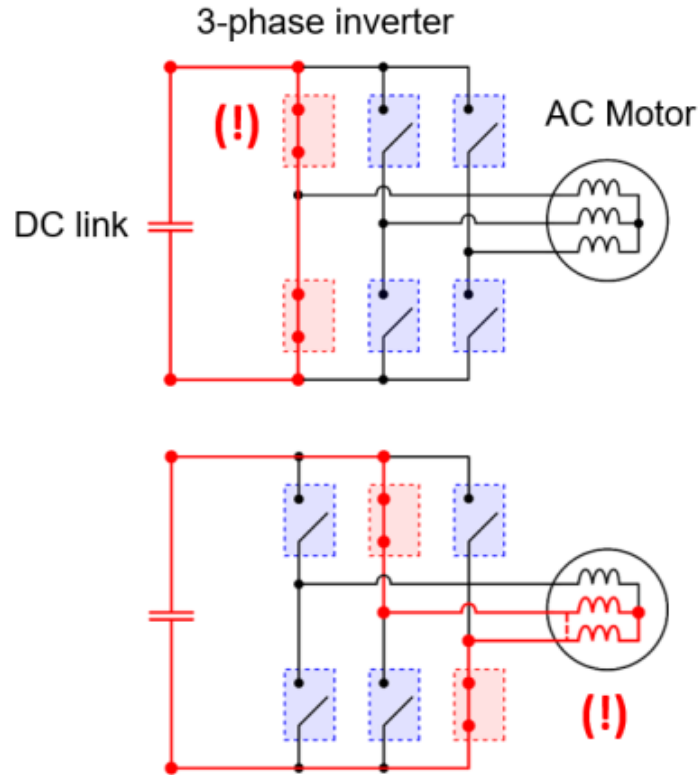


Y. Wu et al., **U.S. Patents** 9443849, 8803246 & 9171910

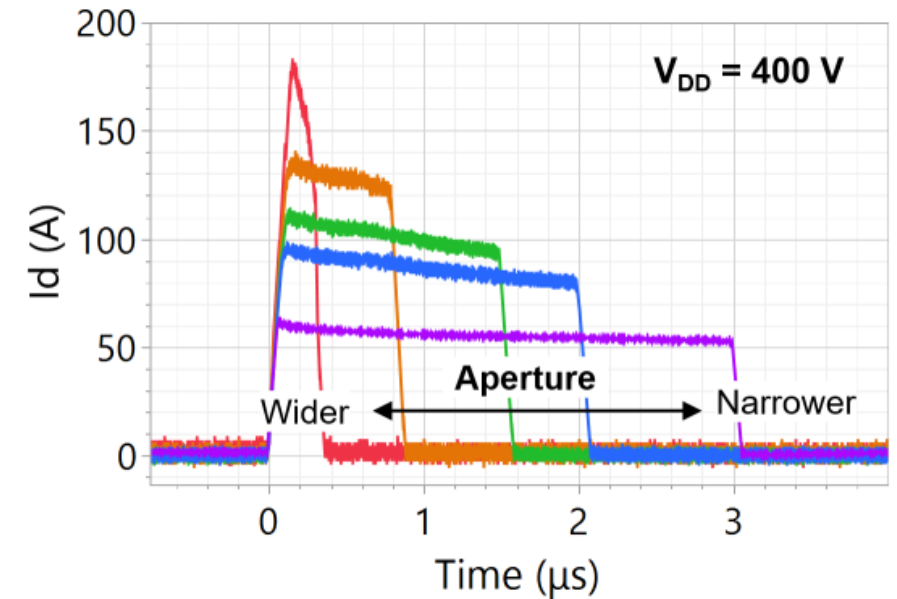


Reduces the saturation current to achieve long SCWT, while preserving low  $R_{on}$  ✓

# Short-Circuit Capability



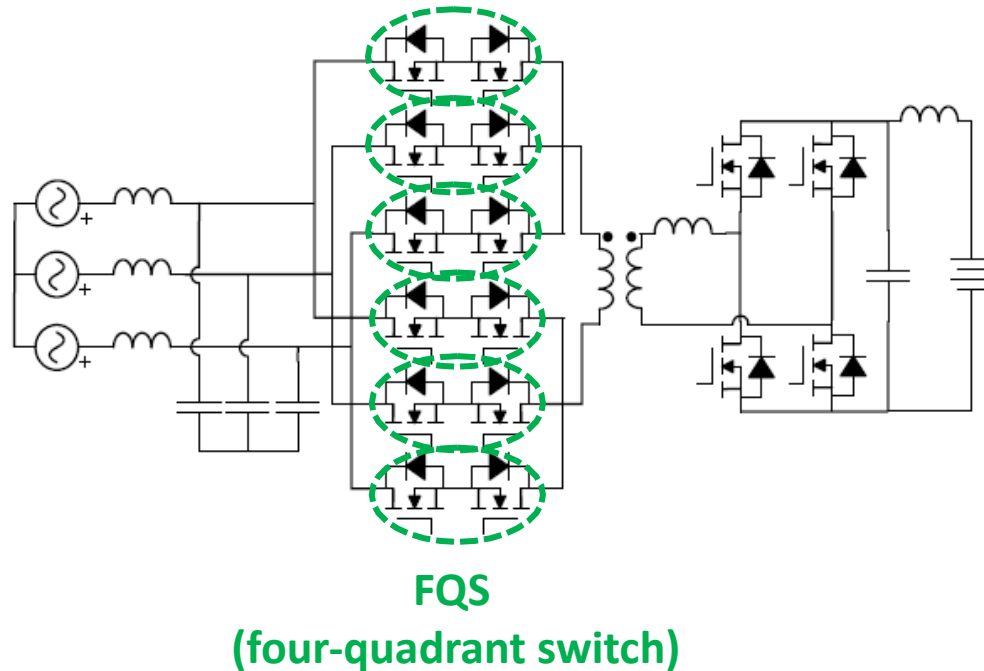
Y. Wu *et al.*, U.S. Patents 9443849, 8803246 & 9171910



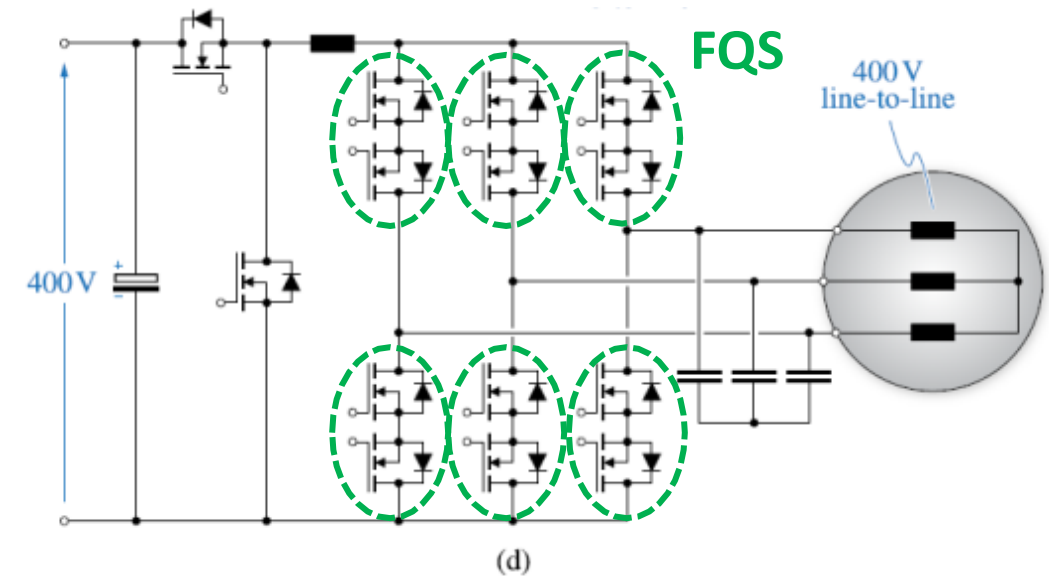
D. Bisi *et al.* APEC 2022

Patented, low-cost and reliable solution to increase Short-Circuit Withstanding Time of GaN HEMTs with limited penalty in on-state resistance.

## Matrix Converters (Single Stage OBC)



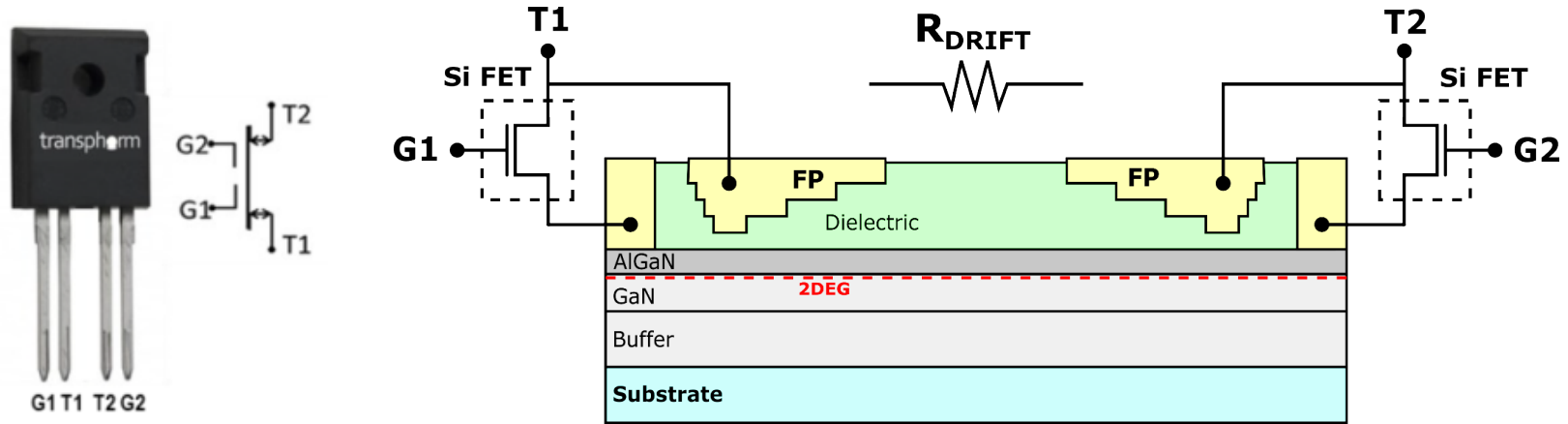
## Current-Source Inverter (CSI)



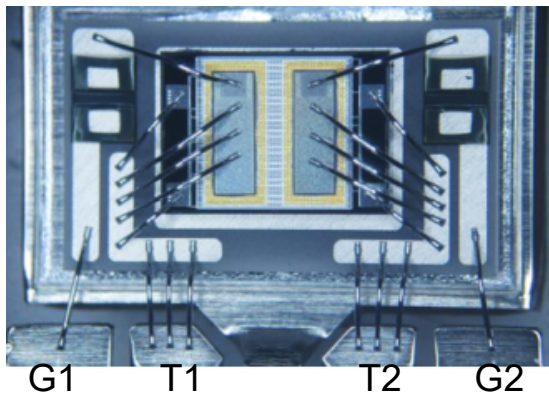
Emerging converter topologies now at academic research stage. Use FQS devices (difficult with IGBTs and SiC, easier with GaN).

**Reference:** Thomas M. Jahns, "The Incredible Shrinking Motor Drive", *Digital Object Identifier 10.1109/MPEL.2020.3011275*

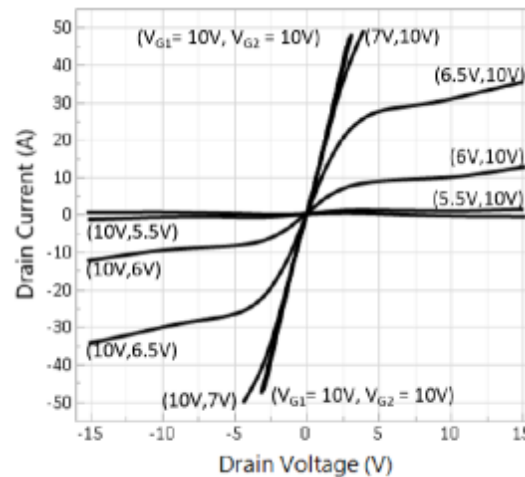
# GaN Four Quadrant Switch (FQS)



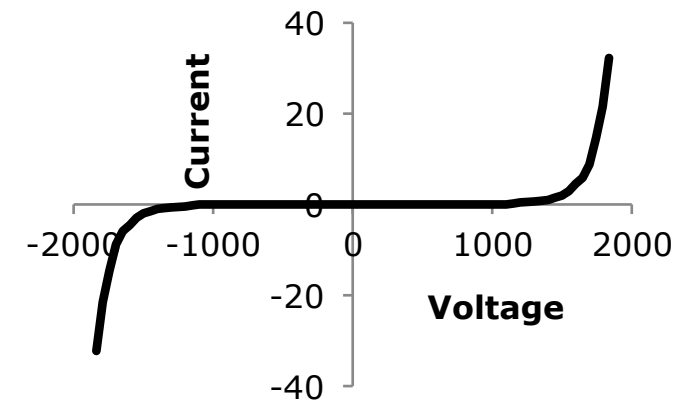
- **Shared Drift region.**
- Efficient integration thanks to GaN lateral architecture.



**On-state**



**Off-state**



- Superior switching performance
- Wide Voltage Range (up to 1.2 kV)
- Wide Power Range (45 – 10 kW+)
- Demonstrated Reliability (AEC Q101, 175°C)
- Short-Circuit Capable
- Four-quadrant Switch capable



---

# Thank you

By, Davide Bisi

Email: [dbisi@transphormusa.com](mailto:dbisi@transphormusa.com)

Phone: +1-805-456-1300 x312



## Transphorm Copyright Notice

---

This presentation is protected by U.S. and international copyright laws. Reproduction and distribution of the presentation or any content herein without written permission of the sponsor is prohibited.

© 2023 Transphorm, Inc.

